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# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

Semiconductor devices - STANDARD PREVIEW Part 16-1: Microwave integrated circuits - Amplifiers (Standards.iten.al)

Dispositifs à semiconducteurs – <u>IEC 60747-16-1:2001</u> Partie 16-1: Circuits intégrés hyperfréquences – Amplificateurs 7d37a7a17663/iec-60747-16-1-2001





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# INTERNATIONAL STANDARD

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Semiconductor devices – STANDARD PREVIEW Part 16-1: Microwave integrated circuits – Amplifiers

Dispositifs à semiconducteurs <u>TEC 60747-16-1:2001</u> Partie 16-1: Circuits intégrés hyperfréquences Amplificateurs 7d37a7a17663/iec-60747-16-1-2001

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## CONTENTS

FO	REWC	DRD	4
1	Scop	e	6
2	Norm	ative references	6
3	Term	inology	6
4	Esse	ntial ratings and characteristics	8
	4.1	General	8
	4.2	Application related description	9
	4.3	Specification of the function	. 10
	4.4	Limiting values (absolute maximum rating system)	.11
	4.5	Operating conditions (within the specified operating temperature range)	.13
	4.6	Electrical characteristics	. 13
	4.7	Mechanical and environmental ratings, characteristics and data	. 15
	4.8	Additional information	. 15
5	Meas	uring methods General <b>iTeh STANDARD PREVIEW</b>	. 15
	5.1		
	5.2	Linear (power) gain ( <b>Gatandards.iteh.ai</b> )	. 16
	5.3	Linear (power) gain flatness ( $\Delta G_{\text{lin}}$ )	. 18
	5.4	Power gain $(G_p)$ https://standards.iteh.ai/catalog/standards/sist/59b82cde-91fc-4c78-9d33-	. 19
	5.5	(Power) gain flatness (\(\Delta\G_p^2\))7a1.7663/iec-60747-16-1-2001.	
	5.6	(Maximum available) gain reduction ( $\Delta G_{red}$ )	. 20
	5.7	Limiting output power (P <sub>o(Itg)</sub> )	.21
	5.8	Output power (P <sub>o</sub> )	. 22
	5.9	Output power at 1 dB gain compression ( <i>P</i> <sub>o(1dB)</sub> )	.23
	5.10	Noise figure (F)	. 24
	5.11	Intermodulation distortion $(P_n/P_1)$ (two-tone)	.26
	5.12	Power at the intercept point (for intermodulation products) $(P_{n(IP)})$	.28
	5.13	Magnitude of the input reflection coefficient (input return loss) ( $ s_{11} $ )	.29
	5.14	Magnitude of the output reflection coefficient (output return loss) ( $ s_{22} $ )	. 30
	5.15	Magnitude of the reverse transmission coefficient (isolation) ( $ s_{12} $ )	. 34
	5.16	Conversion coefficient of amplitude modulation to phase modulation ( $\alpha_{(AM-PM)}$ )	.35
	5.17	Group delay time (t <sub>d(grp)</sub> )	. 37
	5.18		
	5.19	<i>n</i> th order harmonic distortion ratio $(P_{\text{nth}}/P_1)$	
	5.20	Output noise power (P <sub>N</sub> )	
	5.21	Spurious intensity under specified load VSWR ( $P_{sp}/P_{o}$ )	.43

Figure 1 – Circuit for the measurements of linear gain	16
Figure 2 – Basic circuit for the measurement of the noise figure	24
Figure 3 – Basic circuit for the measurements of two-tone intermodulation distortion	26
Figure 4 – Circuit for the measurements of magnitude of input/output reflection coefficient (input/output return loss)	29
Figure 5 – Circuit for the measurement of output reflection coefficient	32
Figure 6 – Circuit for the measurement of isolation	34
Figure 7 – Basic circuit for the measurement of $\alpha_{(AM-PM)}$	35
Figure 8 – Circuit for the measurement of the power added efficiency	38
Figure 9 – Circuit for the measurements of the nth order harmonic distortion ratio	40
Figure 10 – Circuit diagram for the measurement of the output noise power	42
Figure 11 – Circuit diagram for the measurement of the spurious intensity	44

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#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

## **SEMICONDUCTOR DEVICES –**

#### Part 16-1: Microwave integrated circuits – Amplifiers

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International Standard IEC 60747-16-1 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

This bilingual version (2012-09) corresponds to the monolingual English version, published in 2001-11.

The text of this standard is based on the following documents:

FDIS	Report on voting
47E/200/FDIS	47E/204/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

The French version of this standard has not been voted upon.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2004. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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## **SEMICONDUCTOR DEVICES –**

#### Part 16-1: Microwave integrated circuits – Amplifiers

#### 1 Scope

This part of IEC 60747 provides the terminology, the essential ratings and characteristics, as well as the measuring methods for integrated circuit microwave power amplifiers.

#### 2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 60747. For dated references, subsequent amendments to, or revisions of, any of these publications do not apply. However, parties to agreements based on this part of IEC 60747 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of IEC and ISO maintain registers of currently valid International Standards.

IEC 60617-12:1997, Graphical symbols for diagrams – Part 12: Binary logic elements

IEC 60617-13:1993, Graphical symbols for diagrams – Part 13: Analogue elements (standards.iteh.ai)

IEC 60747-1:1983, Semiconductor devices – Discrete devices – Part 1: General

IEC 60747-7:2000, Semiconductor devices – Part 7: Bipolar transistors

IEC 60748-2:1997, Semiconductor devices / contegrated circuits – Part 2: Digital integrated circuits

IEC 60748-3:1986, Semiconductor devices – Integrated circuits – Part 3: Analogue integrated circuits

IEC 60748-4:1997, Semiconductor devices – Integrated circuits – Part 4: Interface integrated circuits

#### 3 Terminology

#### 3.1

linear (power) gain G<sub>lin</sub>

power gain in the linear region of the power transfer curve  $P_0$  (dBm) =  $f(P_i)$ 

NOTE In this region,  $\Delta P_0$  (dBm) =  $\Delta P_i$  (dBm).

#### 3.2

#### linear (power) gain flatness $\Delta G_{lin}$

power gain flatness when the operating point lies in the linear region of the power transfer curve

#### 3.3

#### power gain G<sub>p</sub>, G

ratio of the output power to the input power

NOTE Usually the power gain is expressed in decibels.

#### 3.4

#### (power) gain flatness $\Delta G_{p}$

difference between the maximum and minimum power gain for a specified input power in a specified frequency range

#### 3.5

#### (maximum available) gain reduction $\Delta G_{red}$

difference in decibels between the maximum and minimum power gains that can be provided by the gain control

#### 3.6 Output power limiting

#### 3.6.1

#### output power limiting range

range in which, for rising input power, the output power is limiting

NOTE For specification purposes, the limits of this range are specified by specified lower and upper limit values for the input power.

#### 3.6.2

## limiting output power Po(Itg)

output power in the range where it is limiting

#### 3.6.3

# limiting output power flatness AP o(Itg) DARD PREVIEW

difference between the maximum and minimum output power in the output power limiting (standards.iten.al) range:

## $\Delta P_{o}(\text{Itg}) = P_{o}(\text{Itg,max}) - P_{o}(\text{Itg,min})$

https://standards.iteh.ai/catalog/standards/sist/59b82cde-91fc-4c78-9d33-

## 3.7 intermodulation distortion $P_n/P_i^{rd37a7a17663/iec-60747-16-1-2001}$

ratio of

the output power of the *n*th order component to

the output power of the fundamental component,

at a specified input power

#### 3.8

#### power at the intercept point (for intermodulation products) $P_{n(IP)}$

output power at intersection between the extrapolated output powers of the fundamental component and the *n*th order intermodulation components, when the extrapolation is carried out in a diagram showing the output power of the components (in decibels) as a function of the input power (in decibels)

#### 3.9

#### magnitude of the input reflection coefficient (input return loss) $|s_{11}|$ see 3.5.2.1 of IEC 60747-7

#### 3.10

magnitude of the output reflection coefficient (output return loss)  $|s_{22}|$ see 3.5.2.2 of IEC 60747-7

#### 3.11

magnitude of the reverse transmission coefficient (isolation)  $|s_{12}|$ see 3.5.2.4 of IEC 60747-7

#### 3.12

#### conversion coefficient of amplitude modulation to phase modulation $\alpha_{(AM-PM)}$ quotient of

the phase deviation of the output signal (in degrees) by

the change in input power (in decibels) producing it

#### 3.13

## group delay time td(grp)

ratio of the change, with angular frequency, of the phase shift through the amplifier

NOTE Usually group delay time is very close in value to input-to-output delay time.

#### 3.14

## *n*th order harmonic distortion ratio $P_{\rm nth}/P_{\rm 1}$

ratio of the power of the *n*th order harmonic component measured at the output port of the device to the power of the fundamental frequency measured at the output port for a specified output power

#### 3.15

#### output noise power P<sub>N</sub>

maximum noise power measured at the output port of the device within a specified bandwidth in a specified frequency range for a specified output power

#### 3.16

## spurious intensity under specified load VSWR P<sub>sp</sub>/P<sub>o</sub>REVIEW

ratio of the maximum spurious power measured at the output port of the device to the power of the fundamental frequency measured at the output port under specified load VSWR

#### 747-16-1:2001 4

Essential ratings and characteristics 7d37a7a17663/iec-60747-16-1-2001

#### 4.1 General

#### 4.1.1 Circuit identification and types

#### 4.1.1.1 **Designation and types**

The indication of type (device name), the category of the circuit and the technology applied should be given.

Microwave amplifiers are divided into four categories:

Type A: Low-noise type.

Type B: Auto-gain control type.

Type C: Limiting type.

Type D: Power type.

#### 4.1.1.2 **General function description**

A general description of the function performed by the integrated circuit microwave amplifiers and the features for the application should be made.

#### 4.1.1.3 Manufacturing technology

The manufacturing technology, for example, semiconductor monolithic integrated circuit, thinfilm integrated circuit, micro-assembly, should be stated. This statement should include details of the semiconductor technologies such as MESFET, MISFET, Si bipolar transistor, HBT, etc.

#### 4.1.1.4 Package identification

The following statements should be made:

- a) IEC and/or national reference number of the outline drawing, or drawing of non-standard package including terminal numbering;
- b) principal package material; for example, metal, ceramic, plastic.

#### 4.1.1.5 Main application

The main application should be stated, if necessary. If the device has restrictive applications, these should be stated here.

#### 4.2 Application related description

Information on the application of the integrated circuit and its relation to the associated devices should be given.

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# 4.2.1 Conformance to system and/or interface information (standards.iteh.ai)

It should be stated whether the integrated circuit conforms to an application system and/or interface standard or recommendation  $_{\rm IEC\ 60747-16-1:2001}$ 

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The detailed information about application/systems, equipment and circuits such as VSAT systems, DBS receivers, microwave landing systems, etc., should also be given.

#### 4.2.2 Overall block diagram

A block diagram of the applied systems should be given, if necessary.

#### 4.2.3 Reference data

The most important properties to permit comparison between derivative types should be given.

#### 4.2.4 Electrical compatibility

It should be stated whether the integrated circuit is electrically compatible with other particular integrated circuits or families of integrated circuits or whether special interfaces are required.

Details should be given of the type of the input and output circuits, for example, input/output impedances, d.c. block, open-drain, etc. Interchangeability with other devices, if any, should be given.

#### 4.2.5 Associated devices

If applicable, the following should be stated here:

- devices necessary for correct operation (list with type number, name, and function);
- peripheral devices with direct interfacing (list with type number, name, and function).

#### 4.3 Specification of the function

#### 4.3.1 Detailed block diagram – Functional blocks

A detail block diagram or equivalent circuit information of the integrated circuit microwave amplifiers should be given. The block diagram should be composed of the following:

- 1) functional blocks;
- 2) mutual interconnections among the functional blocks;
- 3) individual functional units within the functional blocks;
- 4) mutual interconnections among the individual functional blocks;
- 5) function of each external connection;
- 6) interdependence between the separate functional blocks.

The block diagram should identify the function of each external connection and, where no ambiguity can arise, can also show the terminal symbols and/or numbers. If the encapsulation has metallic parts, any connection to them from external terminals should be indicated. The connections with any associated external electrical elements should be stated, where necessary.

As additional information, the complete electrical circuit diagram can be reproduced, but not necessarily with indications of the values of the circuit components. The graphical symbol for the function shall be given. This may be obtained from a catalogue of standards of graphical symbols or designed according to the rules of IEC 60617-12 or IEC 60617-13.

## 4.3.2 Identification and function of terminals D PREVIEW

All terminals should be identified on the block diagram (supply terminals, input or output terminals, input/output terminals).

Terminal	Terminal	1) Terminal	<sup>3/1</sup> ec-60747-16-1- 2) Function	Function o	tion of terminal			
number	symbol	designation		3) Input/output identification	4) Type of input/output circuit			

The terminal functions 1)-4) should be indicated in a table as follows:

1) Terminal name

A terminal name to indicate the function terminal should be given. Supply terminals, ground terminals, blank terminals (with abbreviation NC), non-usable terminals (with abbreviation NU) should be distinguished.

2) Function

A brief indication of the terminal function should be given.

- Each function of multi-role terminals, that is terminals that have multiple functions.
- Each function of the integrated circuit selected by mutual pin connections, programming and/or application of function selection data to the function selection pin, such as mode selection pin.
- 3) Input/output identification

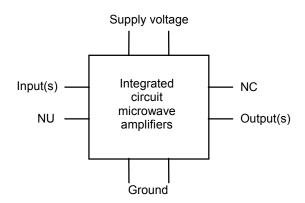
Input, output, input/output, and multiplex input/output terminals should be distinguished.

4) Type of input/output circuits

The type of the input and output circuits, for example, input/output impedances, with or without d.c. block, etc., should be distinguished.

#### 5) Type of ground

If the baseplate of the package is used as ground, this should be stated. Example:



#### 4.3.3 Functional description

The function performed by the circuit should be specified, including the following information:

- basic function;
- relation to external terminals;
- operation mode (for example, set-up method, preference, etc.);
- interrupt handling.

## (standards.iteh.ai)

#### 4.3.4 Family-related characteristics

In this part, all the family specific functional descriptions shall be stated (refer to IEC 60748-2, IEC 60748-3 and IEC 60748-4). 7d37a7a17663/iec-60747-16-1-2001

If ratings and characteristics and function characteristics exist for the family, the relevant part of IEC 60748 should be used (for example, for microprocessors, see IEC 60748-2, Chapter III, Section 3).

NOTE For each new device family, specific items shall be added in the relevant part of IEC 60748.

#### 4.4 Limiting values (absolute maximum rating system)

The table of these values contains the following.

- a) Any interdependence of limiting conditions shall be specified.
- b) If externally connected and/or attached elements, for example heatsinks, have an influence on the values of the ratings, the ratings shall be prescribed for the integrated circuit with the elements connected and/or attached.
- c) If limiting values are exceeded for transient overload, the permissible excess and their duration shall be specified.
- d) Where minimum and maximum values differ during programming of the device, this should be stated.
- e) All voltages are referenced to a specified reference terminal ( $V_{ss}$ ,  $G_{ND}$ , etc.).
- f) In satisfying the following clauses, if maximum and/or minimum values are quoted, the manufacturer must indicate whether he refers to the absolute magnitude or to the algebraic value of the quantity.
- g) The ratings given must cover the operation of the multi-function integrated circuit over the specified range of operating temperatures. Where such ratings are temperaturedependent, this dependence should be indicated.

#### 4.4.1 Electrical limiting values

Limiting values should be specified as follows.

	Parameters	Min.	Max.
(1)	Power supply voltages	+	+
(2)	Power supply currents (where appropriate)		+
(3)	Input voltage(s) (where appropriate)	+	+
(4)	Output voltage(s) (where appropriate)	+	+
(5)	Input current(s) (where appropriate)		+
(6)	Output current(s) (where appropriate)		+
(7)	Other terminal voltage(s) (where appropriate)	+	+
(8)	Other terminal current(s) (where appropriate)		+
(9)	Voltage difference between input and output (where appropriate)	+	+
(10)	Power dissipation		+

The detail specification may indicate those values within the table including note 1 and note 2.

	Parameters (Note 1, Note 2)	Symbols	Min.	Max.	Unit	
	iTeh STAND	ARD P	REVI	EW		
	(standa)	rds.iteb	.ai)			
NO	TE 1 Where appropriate, in accorda	ince with the ty	pe of circu	it considere	ed.	
NO	TE 2 For power supply voltage rang	<b> q</b> 7-16-1:2001				
-	<ul> <li>limitingsválue(s)rofitthei/continuousd.voltáge(s)bát2the 9súpply7terminal(s) with respect to a special electrical reference point: 16-1-2001</li> </ul>					
-	where appropriate, limiting value be	tween specifie	d supply te	rminals;		
-	<ul> <li>when more than one voltage supply is required, a statement should be made as to whether the sequence in which these supplies are applied is significant: if so, the sequence should be stated;</li> </ul>					
-	when more than one supply is r combinations of ratings for these su				state the	

#### 4.4.2 Temperatures

- 1) Operating temperature
- 2) Storage temperature
- 3) Channel temperature (type C and type D only)
- 4) Lead temperature (for soldering).

The detail specification may indicate those values within the table including the note.

F	Parameters (Note)	Symbols	Min.	Max.	Unit		
NOTE	Where appropriate, in accordance with the type of circuit considered.						

#### 4.5 Operating conditions (within the specified operating temperature range)

They are not to be inspected but may be used for quality assessment purpose.

#### 4.5.1 Power supplies positive and/or negative values

#### 4.5.2 Initialization sequences (where appropriate)

If special initialization sequences are necessary, the power supply sequencing and the initialization procedure should be specified.

#### 4.5.3 Input voltage(s) (where appropriate)

- 4.5.4 Output current(s) (where appropriate)
- 4.5.5 Voltage and/or current of other terminal(s)
- 4.5.6 External elements (where appropriate)

#### 4.5.7 Operating temperature range

#### 4.6 Electrical characteristics

The characteristics shall apply over the full operating temperature range, unless otherwise specified.

Each characteristic of 4.6.1 and 4.6.2 should be stated, either

- a) over the specified range of operating temperatures, or
- b) at a temperature of 25 °C, and at maximum and minimum operating temperatures.

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#### 4.6.1 Static characteristics 7d37a7a17663/iec-60747-16-1-2001

The parameters should be specified corresponding to the type as follows.

Parameters	Min.	Typ.ª	Max.	Types			
				Α	В	С	D
4.6.1.1 Power supply current	+	+	+	+	+	+	+
4.6.1.2 Thermal resistance			+			+	+
<sup>a</sup> Optional							

The detail specification may indicate those values within the table.

Characteristics	Symbols	Conditions	Min.	Typ. <sup>a</sup>	Max.	Unit
<sup>a</sup> Optional						

#### 4.6.2 Dynamic or a.c. characteristics

Each dynamic or a.c. electrical characteristic should be stated under specified electrical worst-case conditions with respect to the recommended range of supply voltages, as stated in 4.5.1.